Challenges and Applications in Multimedia and Visual Computing

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Deadline for manuscript submissions:
31 December 2024

Message from the Guest Editors

Dear Colleagues,

The purpose of this Special Issue is to collect and publish new ideas, the latest findings, and state-of-the-art achievements on the topic of challenges and applications in multimedia and visual computing.

Topics of interest include, but are not limited to:

1. Advanced visual feature learning and representation methods;
2. Advanced classification, recognition, and retrieval methods;
3. Advanced 2D/3D object detection and tracking methods;
4. Advanced multi-modal learning and analysis methods;
5. Advanced stereo, multi-view, and 3D content processing methods;
6. Advanced image/video synthesis, editing, compression, visualization and intelligent analysis methods;
7. Advanced image/video restoration and enhancement methods in low-level vision;
8. Advanced quality assessment methods for multimedia;
9. Zero-shot/few-shot methods for visual computing and multimedia;
10. Unsupervised/self-supervised/weakly supervised methods for visual computing and multimedia.

mdpi.com/si/166691

Special Issue

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Message from the Editor-in-Chief

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